Notice of References Cited	Application/Control No. 10/590,319	Applicant(s)/Patent Under Reexamination KANEDA ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	Brian Ensey	2615		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,369,674	05-2008	Miura, Naoki	381/401
	В	US-			
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	F	US-			
	O	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	WO 2005/107315 A1	11-2005	United States	Frasl, Ewald	H04R 7/14
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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